TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ( $L^2$ - $\pi$ -MOSV)

# **2SJ402**

# DC-DC Converter, Relay Drive and Motor Drive Applications

• 4-V gate drive

 Low drain–source ON resistance : RDS (ON) = 29 mQ (typ.)

• High forward transfer admittance :  $|Y_{fs}| = 23 S \text{ (typ.)}$ 

• Low leakage current  $: IDSS = -100 \mu A (max) (VDS = -60 V)$ 

• Enhancement mode :  $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA})$ 

### Absolute Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-60	V	
Drain-gate voltage (Ro	<sub>SS</sub> = 20 kΩ)	$V_{DGR}$	-60	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	I <sub>D</sub>	-30	Α	
	Pulse(Note 1)	I <sub>DP</sub>	-120	Α	
Drain power dissipation	n (Tc = 25°C)	$P_{D}$	100	W	
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	936	mJ	
Avalanche current		I <sub>AR</sub>	-30	Α	
Repetitive avalenche e	nergy (Note 3)	E <sub>AR</sub>	10	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	ange	T <sub>stg</sub>	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.25	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	83.3	°C/W

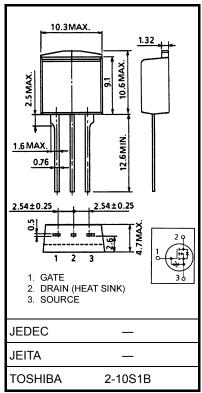
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD}$  = -50 V,  $T_{ch}$  = 25°C (initial), L = 747  $\mu$ H,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = -30 A

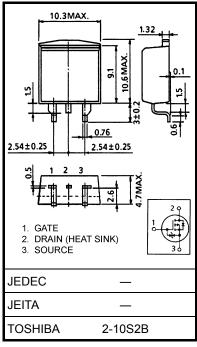
Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm



Weight: 1.5 g (typ.)



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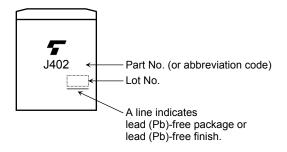
## **Electrical Characteristics (Ta = 25°C)**

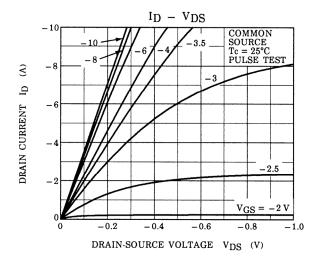
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V	_	_	-100	μA
Drain-source br	eakdown voltage	V (BR) DSS	$I_D$ = -10 mA, $V_{GS}$ = 0 V	-60	_	_	V
Gate threshold v	/oltage	$V_{th}$	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -1 mA	-0.8	_	-2.0	V
Drain-source ON resistance		R <sub>DS (ON)</sub>	V <sub>GS</sub> = -4 V, I <sub>D</sub> = -15 A	-	46	60	mΩ
			$V_{GS} = -10 \text{ V}, I_D = -15 \text{ A}$	1	29	38	11152
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -15 A	14	23	1	S
Input capacitano	ce	C <sub>iss</sub>			3300	_	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		460	_	pF
Output capacitance		Coss			1450	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = 10V$ $V_{DD} = -30V$ $V_{DD} = -30V$	_	20	_	- ns
	Turn-on time	t <sub>on</sub>		_	25	_	
	Fall time	t <sub>f</sub>		_	35	_	
	Turn-off time	t <sub>off</sub>	Duty $\leq 1\%$ , $t_{\mathbf{W}} = 10 \mu\text{s}$	_	130	_	
Total gate charge (Gate-source plus gate-drain)		Qg			110	_	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx -48 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -30 \text{ A}$		75	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>			35	_	

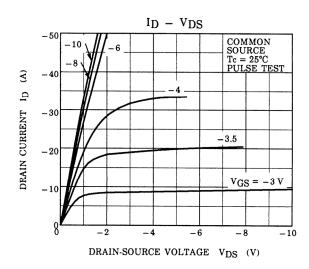
## **Source-Drain Ratings and Characteristics (Ta = 25°C)**

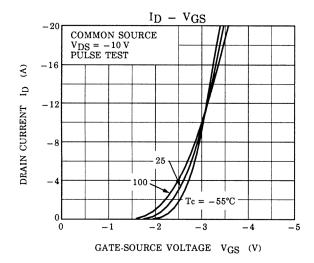
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	-30	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	-120	Α
Forward voltage (diode)	$V_{DSF}$	$I_{DR} = -30 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = -30 A, V <sub>GS</sub> = 0 V		100	_	ns
Reverse recovery charge	Qrr	$dI_{DR}$ / $dt = 50 A / \mu S$		0.16		μC

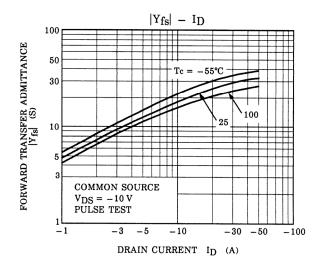
## Marking

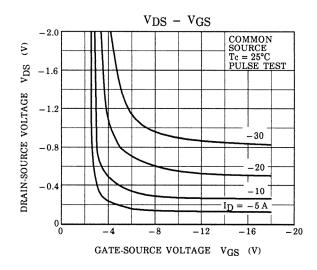


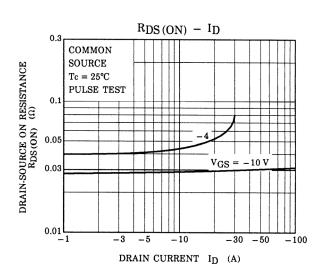




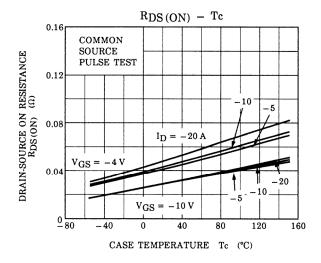


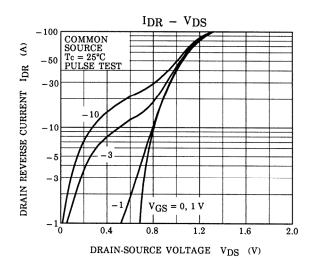


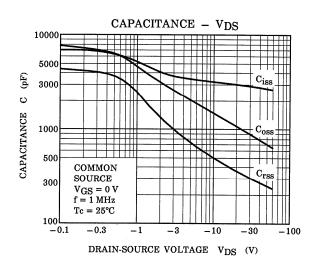


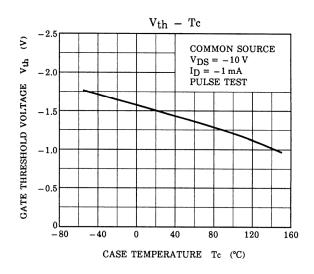


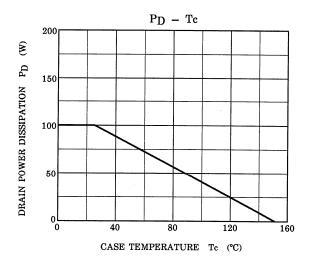
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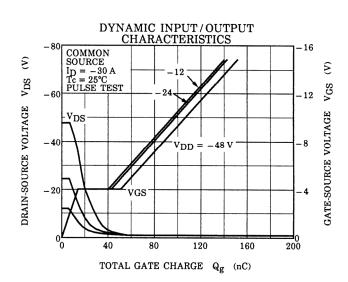


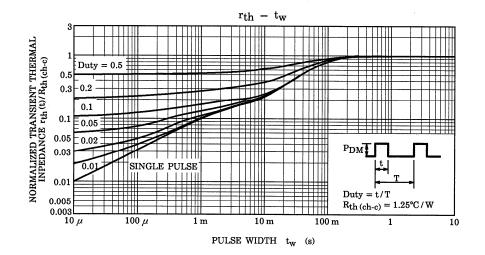


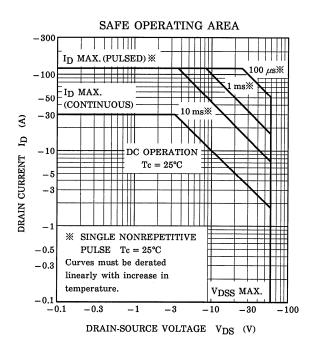


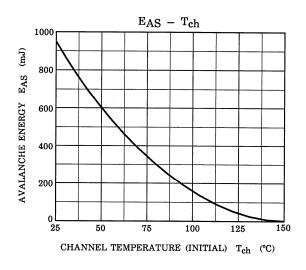


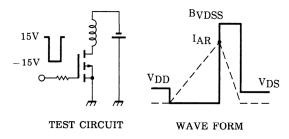












$$\begin{array}{ll} R_G \!=\! 25\Omega \\ V_{DD} \!=\! -50V, \; L \!=\! 747 \mu H \end{array} \qquad E_{AS} \!=\! \frac{1}{2} \cdot L \cdot I^2 \cdot (\frac{B_{VDSS}}{B_{VDSS} \!-\! V_{DD}})$$

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6